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HIGH-SPEED CMOS LOGIC HEX BUFFER/LINE DRIVER, THREE-STATE NON-INVERTING AND INVERTING

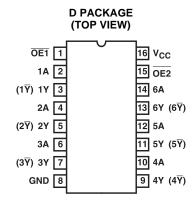
Check for Samples: CD74HC365-Q1, CD74HC366-Q1, CD74HCT365-Q1

FEATURES

- Qualified for Automotive Applications
- Buffered Inputs
- High Current Bus Driver Outputs
- Typical Propagation Delay t_{PLH}, t_{PHL} = 8ns at V_{CC} = 5V, C_L = 15pF, T_A = 25°C
- Fanout (Over Temperature Range)
- Wide Operating Temperature Range . . . –40°C to 125°C
- Balanced Propagation Delay and Transition Times
- Significant Power Reduction Compared to LSTTL Logic ICs
- HC Types
 - 2V to 6V Operation
 - High Noise Immunity: N_{IL} = 30%, N_{IH} = 30% of V_{CC} at V_{CC} = 5V

HCT Types

- 4.5V to 5.5V Operation
- Direct LSTTL Input Logic Compatibility,
 V_{IL}= 0.8V (Max), V_{IH} = 2V (Min)
- CMOS Input Compatibility, II ≤ 1μA at V_{OL},
 V_{OH}



DESCRIPTION

The CD74HC365-Q1, CD74HC366-Q1, and CD74HCT365-Q1 silicon gate CMOS three state buffers are general purpose high-speed non-inverting and inverting buffers. They have high drive current outputs which enable high speed operation even when driving large bus capacitances. These circuits possess the low power dissipation of CMOS circuitry, yet have speeds comparable to low power Schottky TTL circuits. Both circuits are capable of driving up to 15 low power Schottky inputs.

The CD74HC365-Q1 and CD74HCT365-Q1 are non-inverting buffers, whereas the CD74HC366-Q1 is an inverting buffer. These devices have two three-state control inputs (OE1 and OE2) which are NORed together to control all six gates.

The 'HCT365-Q1 logic families are speed, function and pin compatible with the standard LS logic family.

ORDERING INFORMATION⁽¹⁾

T _A	PACKAGE ⁽²⁾		AGE ⁽²⁾ ORDERABLE PART NUMBER	
			CD74HC366QDRQ1	HC366Q
-40°C to 125°C	C to 125°C SOIC – D	Reel of 2500	CD74HC365QDRQ1	Product Preview
			CD74HCT365QDRQ1	Product Preview

- (1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at www.ti.com.
- Package drawings, thermal data, and symbolization are available at www.ti.com/packaging.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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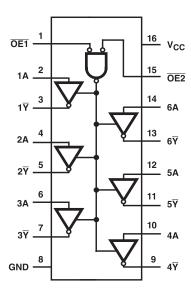
FUNCTIONAL DIAGRAMS

CD74HC365-Q1, CD74HCT365-Q1

16 OE1 v_{cc} 2 15 1A OE2 14 13 6Y 5 5A 6 3A 10 8 GND

CD74HC366-Q1

Instruments



TRUTH TABLE(1)

	INPUTS	OUTPUTS (Y)			
OE1	OE2	Α	HC/HCT365	HC366	
L	L	L	L	Н	
L	L	Н	Н	L	
Χ	Н	X	Z	Z	
Н	Х	Х	Z	Z	

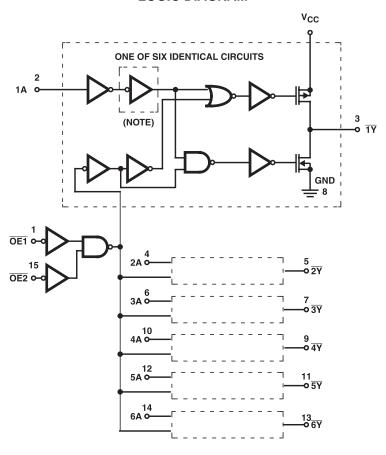
(1) H = High Voltage Level L = Low Voltage Level

X = Don't Care Z = High Impedance (OFF) State



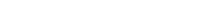
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LOGIC DIAGRAM



NOTE: Inverter not included in CD74HC365-Q1, CD74HCT365-Q1

Figure 1. LOGIC DIAGRAM FOR THE HC/HCT365 AND HC366 (outputs for HC/HCT365 are complements of those shown, i.e., 1Y, 2Y, etc.)



STRUMENTS

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ABSOLUTE MAXIMUM RATINGS(1)

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	PARAMETER		CONDITIONS	VALUE
V _{CC}	DC supply voltage			-0.5V to +7V
I _{IK}	DC input diode current,		$V_{I} < -0.5V \text{ or } V_{I} > V_{CC} + 0.5V$	±20mA
lok	DC output diode current	$V_{O} < -0.5V \text{ or } V_{O} > V_{CC} + 0.5V$	±20mA	
	DC drain current per output		V . 0.5V 57V . V . 0.5V	±35mA
I _O	DC output source or sink current per output pin	$V_{\rm O} > -0.5 V \text{ or } V_{\rm O} < V_{\rm CC} + 0.5 V$	±25mA	
Icc	DC V _{CC} or ground current		,	±50mA
		Human-Body Model		1.5kV
ESD	Electrostatic discharge	Machine Model	200V	
		Field_Induced_Charged [250V	
	Latch up	•		Class I

⁽¹⁾ Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

THERMAL CHARACTERISTICS

over operating free-air temperature range (unless otherwise noted)

	PARAMETER	MIN	MAX	UNIT	
θ_{JA}	Thermal resistance (typical) ⁽¹⁾	D (SOIC) package		73	°C/W
J_T	Maximum junction temperature			150	°C
T _{stg}	Maximum storage temperature range		-65	150	°C
	Maximum lead temperature (soldering 10s)	(SOIC - lead tips only)		300	°C

⁽¹⁾ The package thermal impedance is calculated in accordance with JESD 51-7.

RECOMMENDED OPERATING CONDITIONS

			MIN	MAX	UNIT
\/	Cupply valtage	HC Types	2	6	V
V _{CC}	Supply voltage	HCT Types	4.5	5.5	
VI	DC Input voltage		0	V _{CC}	V
Vo	DC Output voltage		0	V _{CC}	V
T_A			-40	125	°C
		2 V		1000	
	Input Rise and Fall Time	4.5 V		500	ns
		6 V		400	



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ELECTRICAL CHARACTERISTICS

over operating free-air temperature range (unless otherwise noted)

	DADAMETED		TEST CON	DITIONS	V 00		25°C		-40°C TO	UNITS	
	PARAMETER		V _I (V)	I _O (mA)	V _{CC} (V)	MIN	TYP	MAX	MIN	MAX	UNITS
нс т	ypes										
					2	1.5	-	-	1.5		
V_{IH}	High-level input voltage	e	-	-	4.5	3.15	-	-	3.15		V
					6	4.2	-	-	4.2	-	
					2	-	-	0.5	-	0.5	
V_{IL}	Low-level input voltage		-	-	4.5	-	-	1.35	-	1.35	V
					6	-	-	1.8	-	1.8	
					2	1.9	-	-	1.9	-	
	LPak lavel sydned	CMOS		-0.02	4.5	4.4	-	-	4.4	-	
V_{OH}	High-level output voltage loads		V_{IH} or V_{IL}		6	5.9	-	-	5.9	-	V
	g	TTL		-6	4.5	3.98	-	-	3.7	-	
		116		-7.8	6	5.48	-	-	5.2	-	
					2	-	-	0.1	-	0.1	
		CMOS		0.02	4.5	-	-	0.1	-	0.1	
V_{OL}	Low-level output voltage loads		V_{IH} or V_{IL}		6	-	-	0.1	-	0.1	V
	· · · · · · · · · · · · · · · · · · ·	TTL		6	4.5	-	-	0.26	-	0.4	
		IIL		7.8	6	-	-	0.26	-	0.4	
II	Input leakage current		V _{CC} or GND	-	6	-	-	±0.1	-	±1	μΑ
I_{CC}	Quiescent device curre	nt	V _{CC} or GND	0	6	-	-	8	-	160	μΑ
I _{OZ}	Three-state leakage cu	rrent	V _{IH} or V _{IL}	$V_O = V_{CC}$ or GND	6	-	-	±0.5	-	±10	μΑ
HCT	Types										
V_{IH}	High-level input voltage)	-	ı	4.5 to 5.5	2	-	-	2	-	V
V_{IL}	Low-level input voltage		-	ı	4.5 to 5.5	-	-	0.8	-	0.8	V
\/	High-level output	vel output CMOS	V _{IH} or V _{IL}	-0.02	4.5	4.4	-	-	4.4	-	V
V _{OH}	voltage loads	TTL	VIH OI VIL	-4	4.5	3.98	-	-	3.7	-	V
V _{OL}	Low-level output	CMOS	V _{IH} or V _{IL}	0.02	4.5	-	-	0.1	-	0.1	V
VOL	voltage loads	TTL	VIH OI VIL	4	4.5	-	-	0.26	-	0.4	V
I	Input leakage current		V _{CC} or GND	ı	5.5	-	-	±0.1	-	±1	μΑ
I_{CC}	Quiescent device curre	nt	V _{CC} or GND	0	5.5	-	-	8	-	160	μΑ
ΔI _{CC}	Additional quiescent de current per input pin: 1	evice unit load ⁽¹⁾	V _{CC} - 2.1	-	4.5 to 5.5	-	100	360	-	490	μА
I _{OZ}	Three-state leakage cu	rrent	V _{IH} or V _{IL}	$V_O = V_{CC}$ or GND	5.5	-	-	±0.5	-	±10	μΑ

⁽¹⁾ For dual-supply systems theoretical worst case ($V_1 = 2.4V$, $V_{CC} = 5.5V$) specification is 1.8mA.

HCT Input Loading

INPUT	UNIT LOADS									
ŌE1	0.6									
All Others	0.55									

ISTRUMENTS

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SWITCHING CHARACTERISTICS

Input t_r , $t_f = 6$ ns

	PARAMETER		TEST	V _{CC} (V)	25°0		-40°C TO 125°C	UNITS	
			CONDITIONS	33 ()	TYP MAX		MAX		
HC Types	3								
				2	-	110	165		
		HC365	$C_L = 50pF$	4.5	-	22	33		
		HC365		6	-	19	28		
t _{PLH} ,	Propagation delay, data to		C _L = 15pF	5	9	-	-		
t _{PHL}	outputs			2	-	150	225	ns	
		110000	$C_L = 50pF$	4.5	-	31	45		
		HC366		6	-	26	38		
			C _L = 15pF	5	12	-	-		
				2	-	60	90		
TLH,			C _L = 50pF	4.5	-	12	18	ns	
t _{THL}				6	-	10	15		
Cı	Input capacitance		-	-	-	10	10	pF	
Co	Three-state output capacitance		-	-	-	20	20	pF	
C _{PD}	Power dissipation capacitance(1)(2)	-	5	40	-	-	pF	
НСТ Туре	es								
		HCT365	$C_L = 50pF$	4.5	-	25	38		
	Propagation delay, data to	HC1305	CL = 15pF	5	9	-	-		
PLH, tPHL	outputs	LICTOCC	$C_L = 50pF$	4.5	-	27	41	ns	
	HCT366		CL = 15pF	5	11	-	-		
t _{PLH} , t _{PHL}	Propagation delay, output enab	le and disable to	$C_L = 50pF$	4.5	=	35	53	200	
	outputs		C _L = 15pF	5	14	-	-	ns	
TLH, tTHL	Output transition time		$C_L = 50pF$	4.5	-	12	18	ns	
C _I	Input capacitance	-	-	-	10	10	pF		
Co	Three-state output capacitance		-	-	-	20	20	pF	
C _{PD}	Power dissipation capacitance	1)(2)	-	5	42	-	-	pF	

⁽¹⁾ C_{PD} is used to determine the dynamic power consumption, per inverter. (2) $P_D = V_{CC2} \times f_i$ ($C_{PD} + C_L$), where f_i = input frequency, C_L = output load capacitance, V_{CC} = supply voltage



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TEST CIRCUIT AND WAVEFORMS

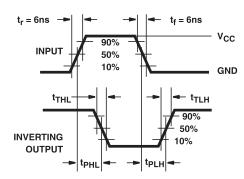


Figure 2. HC and HCU Transition Times and Propagation Delay Times, Combination Logic

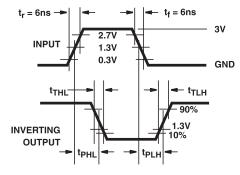


Figure 3. HCT Transition Times and Propagation Delay Times, Combination Logic

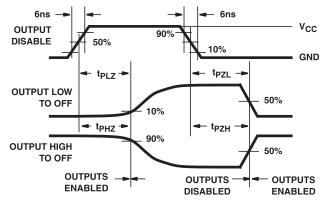


Figure 4. HC Three-State Propagation Delay Waveform

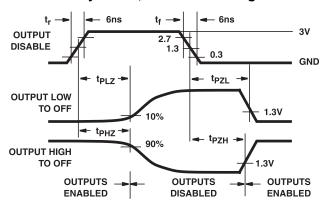
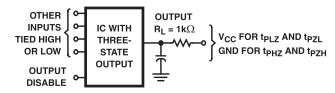


Figure 5. HCT Three-State Propagation Delay Waveform



NOTE: Open drain waveforms t_{PLZ} and t_{PZL} are the same as those for three-state shown on the left. The test circuit is Output $R_L = 1k\Omega$ to V_{CC} , $C_L = 50pF$.

Figure 6. HC and HCT Three-State Propagation Delay Test Circuit



PACKAGE OPTION ADDENDUM

11-Apr-2013

PACKAGING INFORMATION

Orderable Device		Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Top-Side Markings	Samples
	(1)		Drawing		Qty	(2)		(3)		(4)	
CD74HC366QDRQ1	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	HC366Q	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free** (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) Multiple Top-Side Markings will be inside parentheses. Only one Top-Side Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Top-Side Marking for that device.

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OTHER QUALIFIED VERSIONS OF CD74HC366-Q1:

Catalog: CD74HC366





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Military: CD54HC366

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications

D (R-PDS0-G16)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.



D (R-PDSO-G16)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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